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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/018,846	KATO ET AL.	
Examiner	Art Unit	
Daniel Tekle	2621	

SEARCHED				
Class	Subclass	Date	Examiner	
386	68	11/21/2006	DT	
386	70	11/21/2006	DT	
386	95	11/21/2006	DT	
386	125	11/21/2006	DT	
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
East data base (MPEG and arrival adj time; MPEG and arrival adj time with PCR or ATS with transport	. 11/20/2006	DT
Inventer search	11/20/2006	DT
QEM .	11/21/2006	DŢ
Boccio Vincent	11/16/2006	DT
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